Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/606,184	KOJIMA ET AL.
Examiner	Art Unit

Shew-Fen Lin

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	SEARCHED		
Class	Subclass	Date	Examiner
707	1-10	9/1/2006	SFL
707	100-104	9/1/2006	SFL
707	200-206	9/1/2006	SFL

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
EAST	9/1/2006	SFL